

**Main Product Characteristics:**

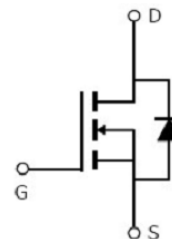
$V_{DSS}$	-100V
$R_{DS(on)}$	170m $\Omega$ (typ.)
$I_D$	-10A



TO-252 (DPAK)



Marking and pin Assignment



Schematic diagram

**Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature


**Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

**Absolute max Rating:**

Symbol	Parameter	Max.	Units
$I_D$ @ TC = 25°C	Continuous Drain Current, $V_{GS}$ @ -10V <sup>①</sup>	-10	A
$I_D$ @ TC = 100°C	Continuous Drain Current, $V_{GS}$ @ -10V <sup>①</sup>	-6.5	
$I_{DM}$	Pulsed Drain Current <sup>②</sup>	-40	
$P_D$ @TC = 25°C	Power Dissipation <sup>③</sup>	54	W
	Linear Derating Factor	0.43	W/°C
$V_{DS}$	Drain-Source Voltage	-100	V
$V_{GS}$	Gate-to-Source Voltage	± 30	V
$E_{AS}$	Single Pulse Avalanche Energy @ L=0.3mH	38	mJ
$I_{AS}$	Avalanche Current @ L=0.3mH	-16	A
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	°C

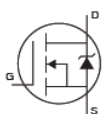
## Thermal Resistance

Symbol	Characterizes	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-case <sup>③</sup>	—	2.3	°C/W
$R_{\theta JA}$	Junction-to-ambient ( $t \leq 10s$ ) <sup>④</sup>	—	62	°C/W

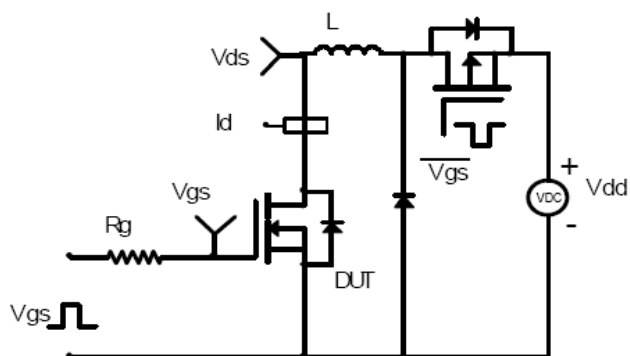
## Electrical Characterizes @ $T_A=25^\circ\text{C}$ unless otherwise specified

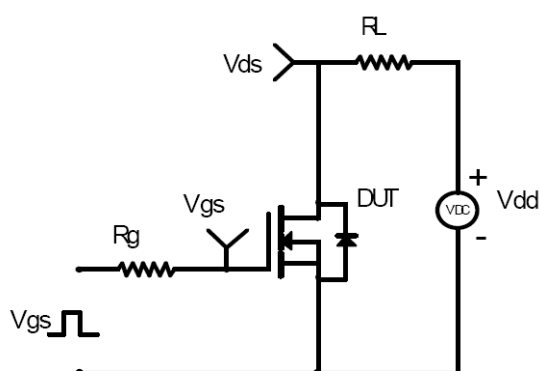
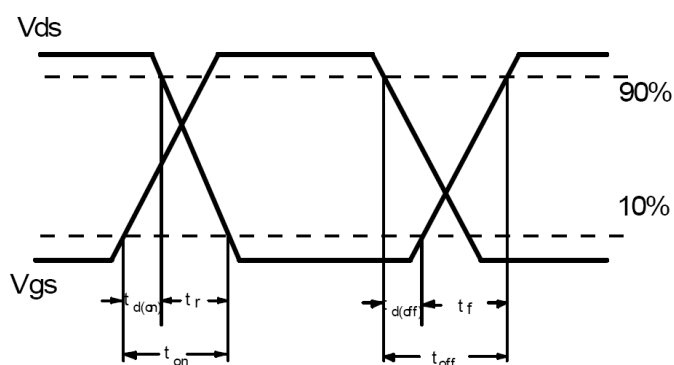
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	-100	—	—	V	$V_{GS} = 0V, I_D = -250\mu A$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	170	210	m $\Omega$	$V_{GS}=-10V, I_D = -5A$
		—	190	230		$V_{GS}=-4.5V, I_D = -2A$
$V_{GS(th)}$	Gate threshold voltage	-1	—	-3	V	$V_{DS} = V_{GS}, I_D = -250\mu A$
$I_{DSS}$	Drain-to-Source leakage current	—	—	-1	$\mu A$	$V_{DS} = -100V, V_{GS} = 0V$
$I_{GSS}$	Gate-to-Source forward leakage	—	—	100	nA	$V_{GS} = 30V$
		—	—	-100		$V_{GS} = -30V$
$Q_g$	Total gate charge	—	20	—	nC	$I_D = -5A,$ $V_{DS} = -80V,$ $V_{GS} = -10V$
$Q_{gs}$	Gate-to-Source charge	—	3.5	—		
$Q_{gd}$	Gate-to-Drain("Miller") charge	—	4.6	—		
$t_{d(on)}$	Turn-on delay time	—	18	—	ns	$V_{GS} = -10V, V_{DS} = -50V,$ $R_{GEN} = 25\Omega$ $I_D = -5A$
$t_r$	Rise time	—	8	—		
$t_{d(off)}$	Turn-Off delay time	—	100	—		
$t_f$	Fall time	—	30	—		
$C_{iss}$	Input capacitance	—	1419	—	pF	$V_{GS} = 0V$ $V_{DS} = -25V$ $f = 1MHz$
$C_{oss}$	Output capacitance	—	89	—		
$C_{rss}$	Reverse transfer capacitance	—	45	—		

## Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	-10	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$I_{SM}$	Pulsed Source Current (Body Diode)	—	—	-20	A	
$V_{SD}$	Diode Forward Voltage	—	—	-1.2	V	$I_S = -1A, V_{GS} = 0V$
$t_{rr}$	Reverse Recovery Time	—	27	—	nS	$T_J = 25^\circ\text{C}, I_F = -5A,$ $di/dt = 100A/\mu s$
$Q_{rr}$	Reverse Recovery Charge	—	24	—	nC	

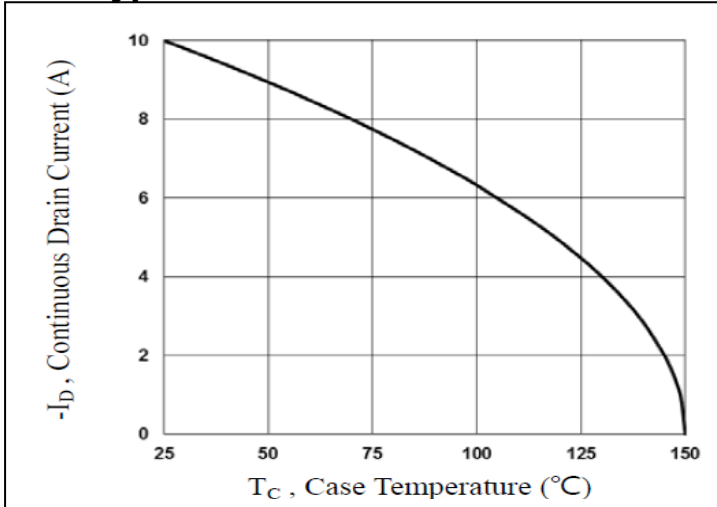
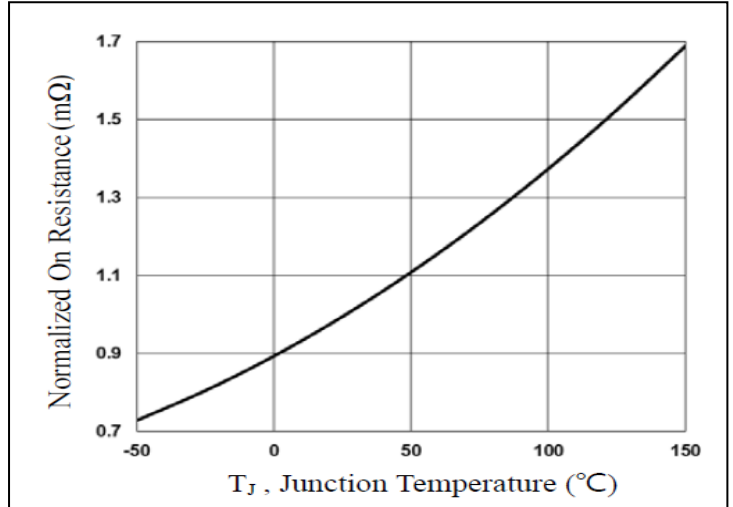
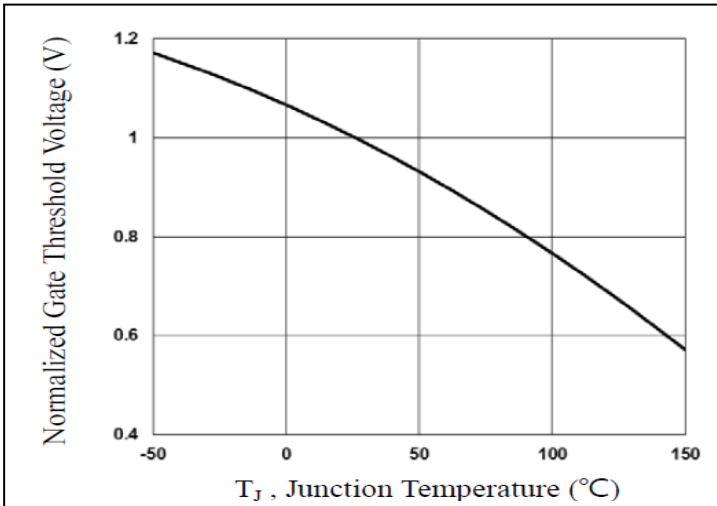
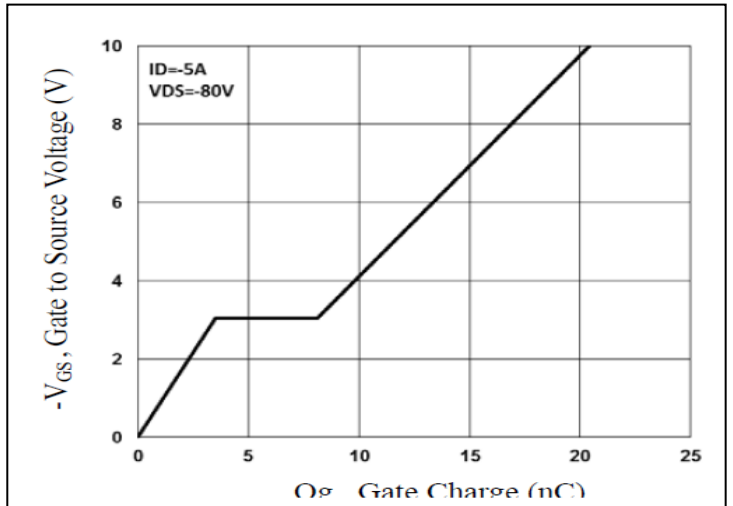
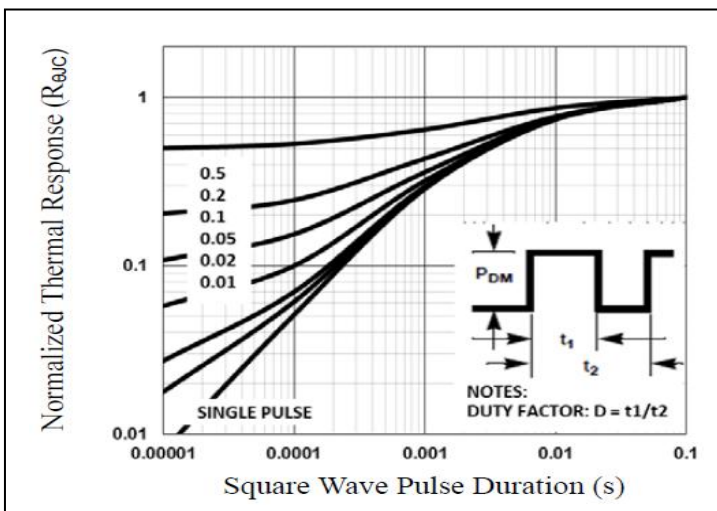
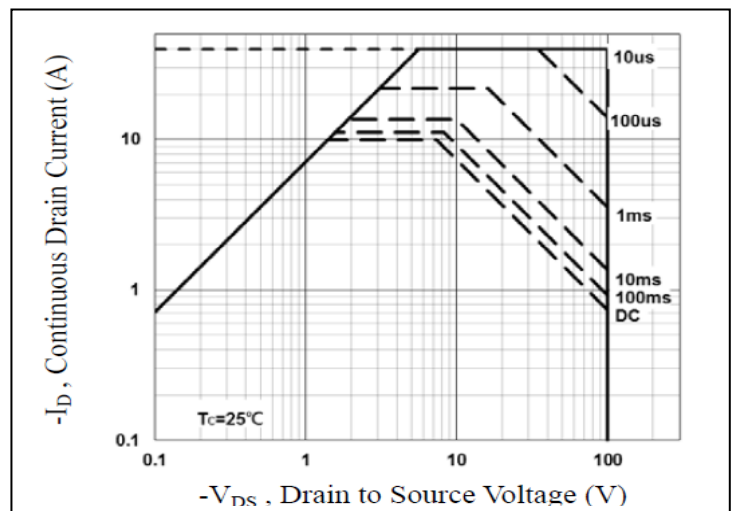
## Test circuits and Waveforms

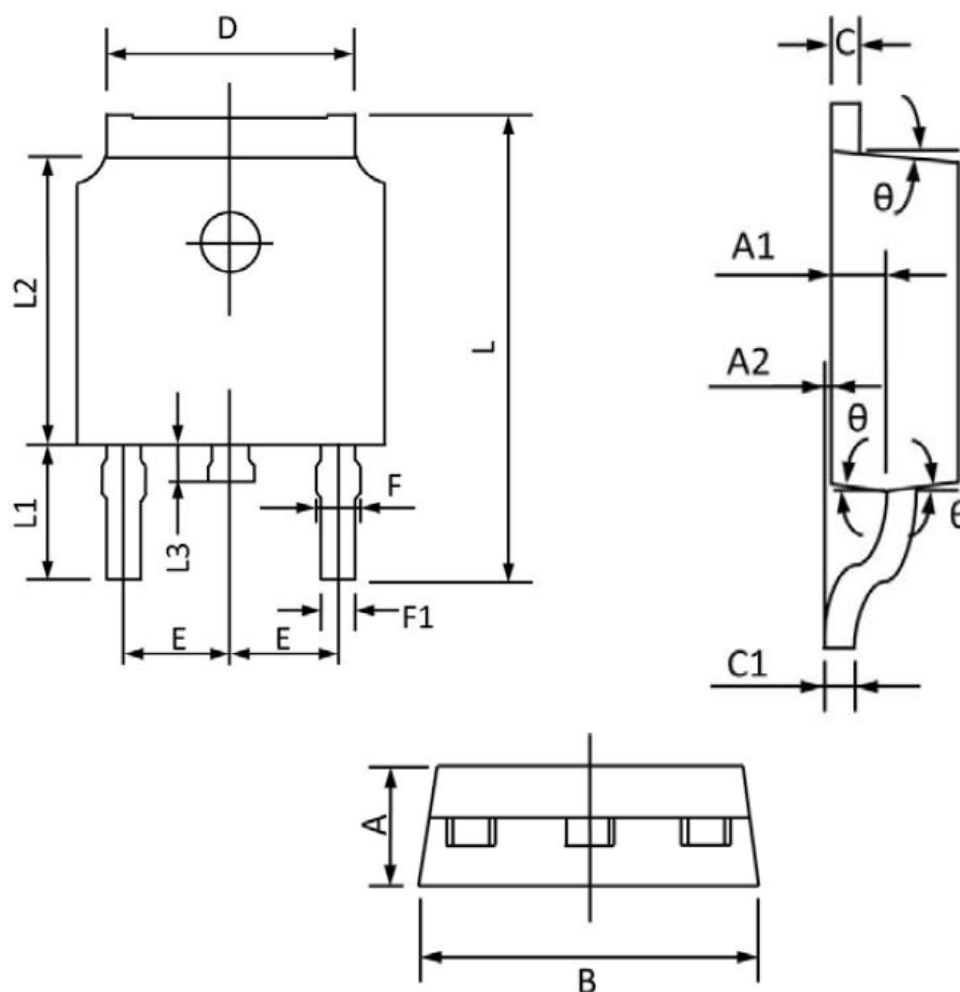
**EAS Test Circuit:**

**Gate charge test circuit:**

**Switching Time Test Circuit:**

**Switching Waveforms:**


### Notes:

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$

**Typical electrical and thermal characteristics**

**Figure 1: Continuous Drain Current Vs.  $T_C$** 

**Figure 2: Normalized  $R_{dson}$  Vs.  $T_J$** 

**Figure 3: Normalized  $V_{th}$  Vs.  $T_J$** 

**Figure 4: Gate Charge waveform**

**Figure 5: Normalized Transient Impedance**

**Figure 6: Maximum Safe Operation Area**

**Mechanical Data:**


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	2.20	2.40	0.087	0.094
A1	0.91	1.11	0.036	0.044
A2	0.00	0.15	0.000	0.006
B	6.50	6.70	0.256	0.264
C	0.46	0.580	0.018	0.230
C1	0.46	0.580	0.018	0.030
D	5.10	5.46	0.201	0.215
E	2.186	2.386	0.086	0.094
F	0.74	0.94	0.029	0.037
F1	0.660	0.860	0.026	0.034
L	9.80	10.40	0.386	0.409
L1	2.9REF		0.114REF	
L2	6.00	6.20	0.236	0.244
L3	0.60	1.00	0.024	0.039
θ	3°	9°	3°	9°

**Ordering and Marking Information**
**Device Marking: SSF1021D**

**Package (Available)**  
**TO-252(DPAK)**  
**Operating Temperature Range**  
**C : -55 to 150 °C**

**Devices per Unit**

Package Type	Units/Tape	Tapes/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
TO-252	2500	2	5000	7	35000
TO-252	2500	1	2500	10	25000
TO-252	800	5	4000	8	32000

**Reliability Test Program**

Test Item	Conditions	Duration	Sample Size
High Temperature Reverse Bias(HTRB)	$T_j=125^{\circ}\text{C}$ to $150^{\circ}\text{C}$ @ 80% of Max $V_{DSS}/V_{CES}/V_R$	168 hours 500 hours 1000 hours	3 lots x 77 devices
High Temperature Gate Bias(HTGB)	$T_j=150^{\circ}\text{C}$ @ 100% of Max $V_{GSS}$	168 hours 500 hours 1000 hours	3 lots x 77 devices

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